

Customer Code : \_\_\_\_\_

# DATASHEET

DAPU P/N: OS754-A319-66.00MHz-A**Y75NNM66000**

DAPU			Customer Approval
Drew	Audited	Approved	Stamp, please! Thanks!
Date: 2015.12.16			

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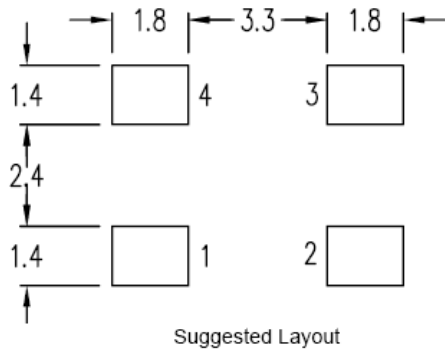


## 1、 Electrical Parameters

Parameters	SYM	Electrical Spec.				Notes
		Min.	Typ.	Max.	Units	
<b>Frequency Stabilities</b>						
Nominal Frequency	F <sub>N</sub>	66.00			MHz	
Oscillation mode		Overtone				
Frequency Stability		-50		+50	× 10 <sup>-6</sup>	incl. 25 °C tolerance, tolerance over operating temperature range, input voltage change, load change, 1 year aging.
Vs. aging /1.year		-3		+3	× 10 <sup>-6</sup>	
<b>RF Output</b>						
Output Waveform		CMOS				
Load	I <sub>OUT</sub>	15			pF	
Output Voltage High	V <sub>OH</sub>	90% V <sub>CC</sub>			V	
Output Voltage Low	V <sub>OL</sub>			10% V <sub>CC</sub>	V	
Rise / Fall Time	T <sub>r</sub> / T <sub>f</sub>			4	ns	
Symmetry	SYM	50 ± 10%				
Start-up Time	T <sub>S</sub>			3	ms	
<b>Supply Voltage</b>						
Supply Voltage	V <sub>CC</sub>	3.3 ± 10%			V	
Input Current	I <sub>CC</sub>			45	mA	
Standby Current	V <sub>C</sub>			10	uA	
<b>Enable Control</b>						
Enable Control		Pin 1				
<b>Phase Noise</b>						
Jitter				1	ps	RMS(12KHz to 20MHz)
<b>Environmental Conditions</b>						
Operating Temperature	T <sub>OP</sub>	-40	~	85	°C	
Storage Temperature	T <sub>ST</sub>	-55	~	125	°C	
Temperature Cycle	GB/T 2423.22-2002, Method Nb. Frequency change after test ≤ ±5ppm.					
Low Temperature Storage	GB/T 2423.1-2001, Method Aa. Frequency change after test ≤ ±5ppm.					
High Temperature Storage	GB/T 2423.2-2001, Method Ba. Frequency change after test ≤ ±5ppm.					
Humidity	GB/T 2423.3-2006, Method Cab. Frequency change after test ≤ ±5ppm.					
Vibration	GB/T 2423.10-1995, Method Fc. Frequency change after test ≤ ±5ppm.					
Shock	GB/T 2423.5-1995, Method Ea. Frequency change after test ≤ ±5ppm. No visible damages.					
Drop	GB/T 2423.8-1995, Method Ed. Frequency change after test ≤ ±5ppm. No visible damages.					
Solderability	GB/T 2423.28-2005, Method Tc. Terminals shall be covered more then 95% with solder.					
Terminal Strength	JIS-C-6429 Method 1 & 2. No visible damages.					
Resistance to Soldering Heat	GB/T 2423.28-2005, Test Tb Method 1B. Frequency change after test ≤ ±5ppm.					

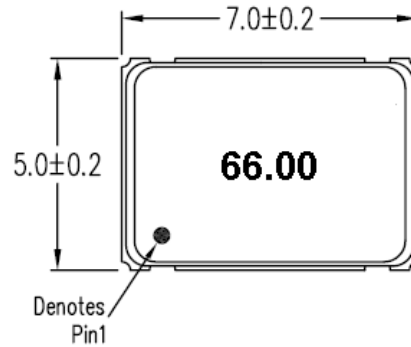
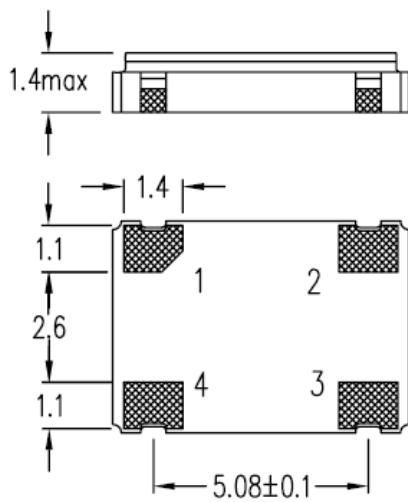


## 2、 Mechanical Structure(mm)



### PIN CONNECTION

1	Enable/Disable*
2	GND
3	Output
4	VDD



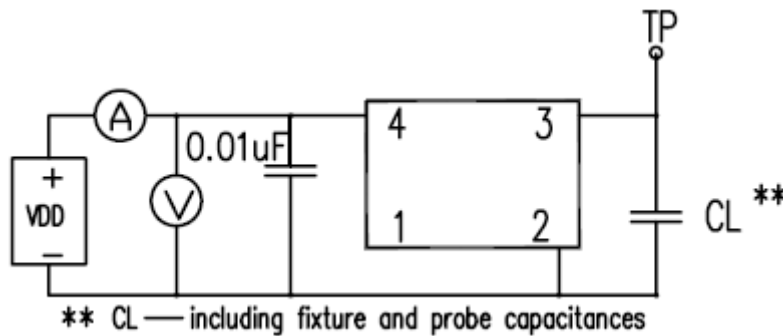
**Note1:** Tolerance  $\pm 0.20\text{mm}$  without mark

**Note2:** Referential Weight 0.3g

**Note3:** Enable/disable functional description

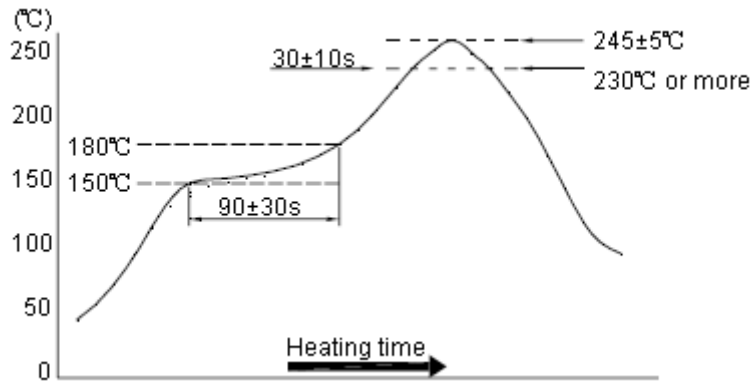
When pin1 goes high ( $\geq 0.7VDD$ ) or open , the oscillator in normal operation and has output in frequency .When pin1 goes low ( $\leq 0.3VDD$ ) , the oscillator stops and the oscillator output (pin3) becomes high impedance.

## 3、 Test circuit

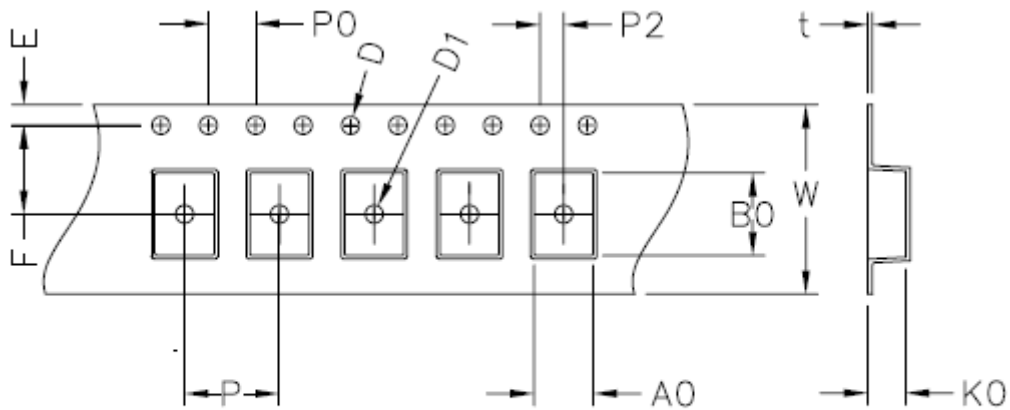




#### 4、 Reflow Soldering Curve (RoHS)



#### 5、 Package: Tape & Reel (mm)



EMBOSSED TYPE DIMENSIONS

ITEM	W+0.3/0.1	A0±0.1	B0±0.1	K0±0.1	P±0.1	F±0.1	t±0.05	Qty
149	16.0	5.5	7.5	2.0	8.0	7.5	0.3	1000

E=1.75±0.1、D=1.5±0.1、D1=1.5+0.25/-0.0、P0=4.0±0.1、P2=2.0±0.1